Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/748,734	NAKAHARA, KEN	
Examiner	Art Unit	

Johannes P. Mondt

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	SEAR	CHED	
Class	Subclass	Date	Examiner
257	79-103	3/21/2005	JPM
372	43-50	3/21/2005	JPM
349	42-53	3/21/2005	JPM
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH (INCLUDING SEA	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
East, IEEE, INSPEC	3/21/200	05 JPM	
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